

**Search Notes**

Application/Control No.

10/661,204

Examiner

Hae M. Hyeon

Applicant(s)/Patent under  
Reexamination

LAIL ET AL.

Art Unit

2839

**SEARCHED**

Class	Subclass	Date	Examiner
Search	Updated	11/06	hnh

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
385	100	11/06	hnh
385	102	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR